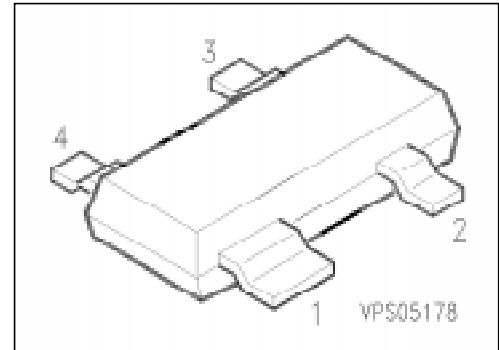


## Silicon Switching Diode Array

**BGX 50 A**

- Bridge configuration
- High-speed switch diode chip



Type	Marking	Ordering Code (tape and reel)	Pin Configuration	Package <sup>1)</sup>
BGX 50 A	U1s	Q62702-G38		SOT-143

### Maximum Ratings per Diode

Parameter	Symbol	Values	Unit
Reverse voltage	$V_R$	50	V
Peak reverse voltage	$V_{RM}$	70	
Forward current	$I_F$	140	mA
Total power dissipation, $T_s = 74\text{ °C}$	$P_{tot}$	210	mW
Junction temperature	$T_j$	150	°C
Storage temperature range	$T_{stg}$	- 65 ... + 150	

### Thermal Resistance

Junction - ambient <sup>2)</sup>	$R_{th\ JA}$	≤ 640	K/W
Junction - soldering point	$R_{th\ JS}$	≤ 360	

<sup>1)</sup> For detailed information see chapter Package Outlines.

<sup>2)</sup> Package mounted on epoxy pcb 40 mm × 40 mm × 1.5 mm/6 cm<sup>2</sup> Cu.

## Electrical Characteristics

at  $T_A = 25\text{ }^\circ\text{C}$ , unless otherwise specified.

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

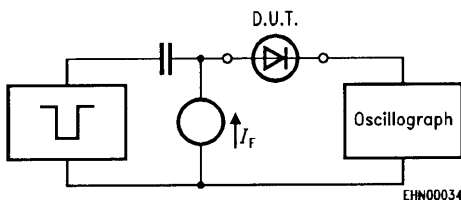
### DC characteristics

Forward voltage per diode $I_F = 100\text{ mA}$	$V_F$	–	–	1.3	V
Reverse current per diode $V_R = 50\text{ V}$ $V_R = 50\text{ V}, T_A = 150\text{ }^\circ\text{C}$	$I_R$	–	–	0.2 100	$\mu\text{A}$

### AC characteristics

Diode capacitance $V_R = 0, f = 1\text{ MHz}$	$C_D$	–	–	1.5	pF
Reverse recovery time $I_F = 10\text{ mA}, I_R = 10\text{ mA}, R_L = 100\text{ }\Omega$ measured at $I_R = 1\text{ mA}$	$t_{rr}$	–	–	6	ns

### Test circuit for reverse recovery time

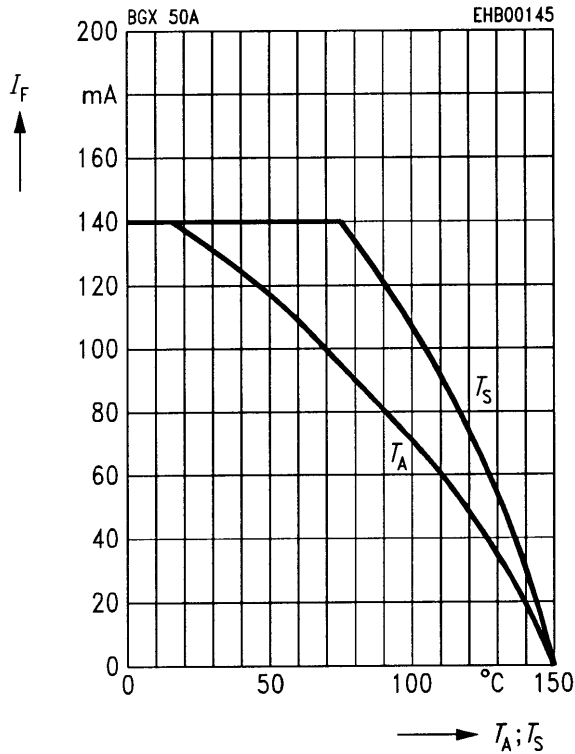


Pulse generator:  $t_p = 100\text{ ns}, D = 0.05$   
 $t_r = 0.6\text{ ns}, R_j = 50\text{ }\Omega$

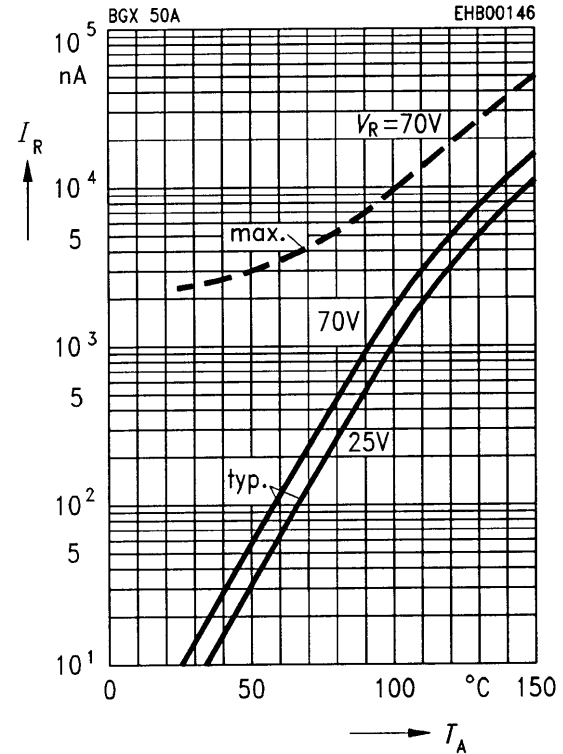
Oscilloscope:  $R = 50\text{ }\Omega$   
 $t_r = 0.35\text{ ns}$   
 $C \leq 1\text{ pF}$

### Forward current $I_F = f(T_A^*; T_S)$

\* Package mounted on epoxy

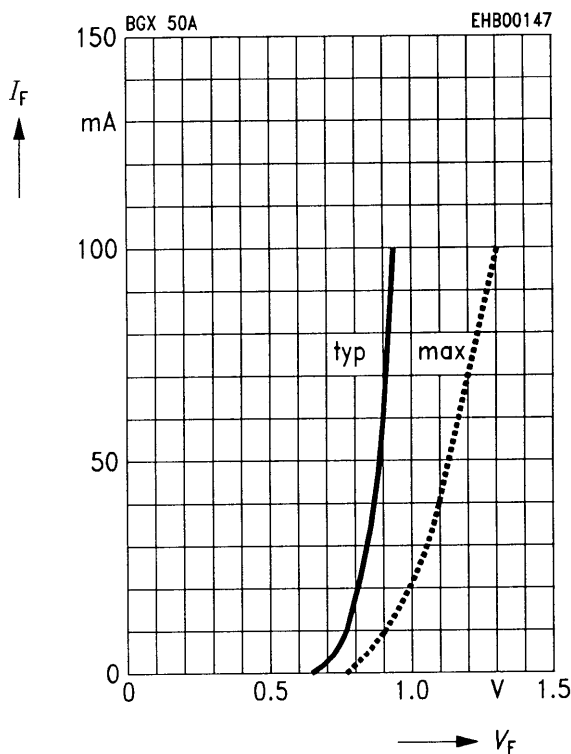


### Reverse current $I_R = f(T_A)$



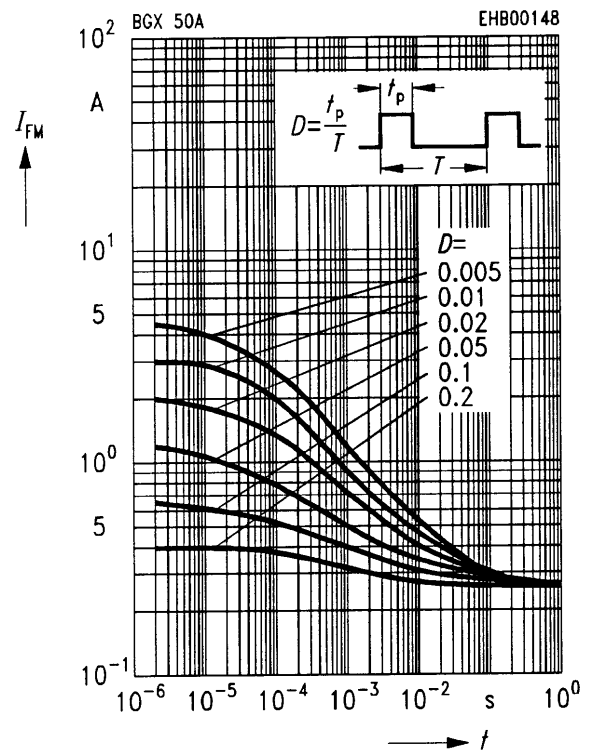
### Forward current $I_F = f(V_F)$

$T_A = 25^\circ\text{C}$



### Peak forward current $I_{FM} = f(t)$

$T_A = 25^\circ\text{C}$



## Forward voltage $V_F = f(T_A)$

